



# IDC04S60C

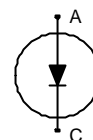
## 2<sup>nd</sup> generation thinQ!<sup>TM</sup> SiC Schottky Diode

### FEATURES:

- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery
- No temperature influence on the switching behavior
- No forward recovery
- High surge current capability

### Applications:

- SMPS, PFC, snubber



| Chip Type | V <sub>BR</sub> | I <sub>F</sub> | Die Size                      | Package      |
|-----------|-----------------|----------------|-------------------------------|--------------|
| IDC04S60C | 600V            | 4A             | 1.146 x 0.968 mm <sup>2</sup> | sawn on foil |

### MECHANICAL PARAMETER:

|                                 |  |                 |
|---------------------------------|--|-----------------|
| Raster size                     | 1.146x 0.968   | mm              |
| Anode pad size                  | 0.909 x 0.731  |                 |
| Area total / active             | 1.11 / 0.74  | mm <sup>2</sup> |
| Thickness                       | 355  | µm              |
| Wafer size                      | 75   | mm              |
| Flat position                   | 0  | deg             |
| Max. possible chips per wafer   | 3461 pcs   |                 |
| Passivation frontside           | Photoimide   |                 |
| Anode metalization              | 3200 nm Al   |                 |
| Cathode metalization            | 1400 nm Ni Ag –system<br>suitable for epoxy and soft solder die bonding                      |                 |
| Die bond                        | Electrically conductive glue or solder   |                 |
| Wire bond                       | Al, ≤ 350µm  |                 |
| Reject Ink Dot Size             | Ø ≥ 0.3 mm   |                 |
| Recommended Storage Environment | store in original container, in dry nitrogen,<br>< 6 month at an ambient temperature of 23°C |                 |



# IDC04S60C

## Maximum Ratings

| Parameter   | Symbol         | Condition                                 | Value      | Unit       |
|---|----------------|---|------------|------------|
| Repetitive peak reverse voltage                       | $V_{RRM}$      |   | 600        | V          |
| DC blocking voltage                                   | $V_{DC}$       |   | 600        |            |
| Continuous forward current limited by $T_{jmax}$      | $I_F$          |   | 4          | A          |
| Surge non repetitive forward current sine halfwave    | $I_{F,SM}$     | $T_C=25^\circ C, t_P=10\text{ ms}$        | 32         |            |
| Repetitive peak forward current limited by $T_{jmax}$ | $I_{F,RM}$     | $T_C=100^\circ C, T_j=150^\circ C, D=0.1$ | 18         |            |
| Non-repetitive peak forward current                   | $I_{F,max}$    | $T_C=25^\circ C, t_P=10\mu s$             | 132        |            |
| Operating junction and storage temperature            | $T_j, T_{stg}$ |   | -55...+175 | $^\circ C$ |

## Static Electrical Characteristics (tested on chip), $T_j=25^\circ C$ , unless otherwise specified

| Parameter             | Symbol | Conditions                     | Value |      |      | Unit    |
|-----------------------|--------|--------------------------------|-------|------|------|---------|
|                       |        |                                | min.  | Typ. | max. |         |
| Reverse current       | $I_R$  | $V_R=600V$<br>$T_j=25^\circ C$ |       | 0.5  | 50   | $\mu A$ |
| Diode forward voltage | $V_F$  | $I_F=4A$<br>$T_j=25^\circ C$   |       | 1.7  | 1.9  | V       |

## Dynamic Electrical Characteristics, at $T_j=25^\circ C$ , unless otherwise specified, tested at component

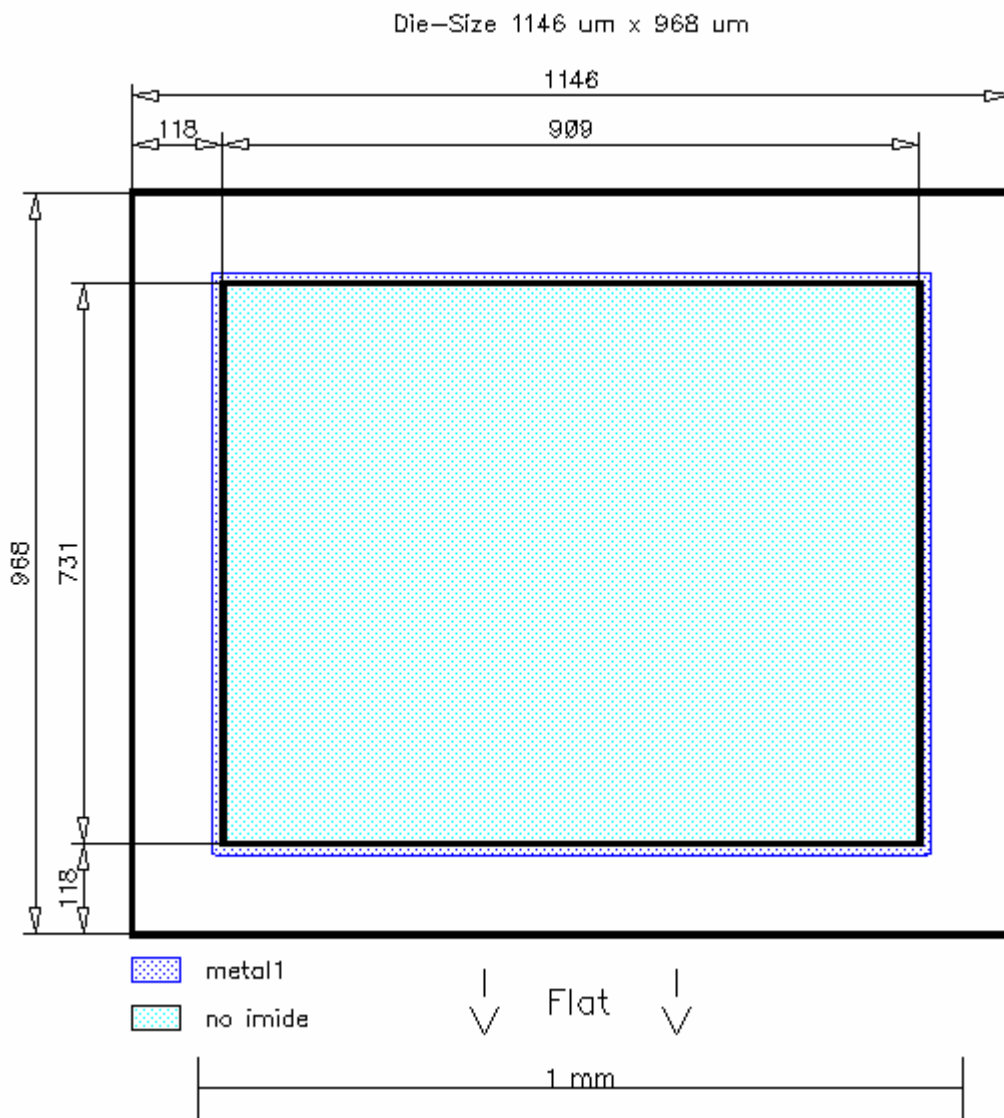
| Parameter                    | Symbol | Conditions  | Value      |      |      | Unit |
|------------------------------|--------|---|------------|------|------|------|
|                              |        |   | min.       | Typ. | max. |      |
| Total capacitive charge      | $Q_C$  | $I_F \leq I_{F,max}$<br>$di/dt=200A/ms$<br>$V_R=400V$ |            | 8    |      | nC   |
| Switching time <sup>1)</sup> | $t_c$  | $V_R=400V$  |            |      | <10  | ns   |
| Total capacitance            | C      | $f=1MHz$  | $V_R=1V$   |      | 130  | pF   |
|                              |        |   | $V_R=300V$ |      | 20   |      |
|                              |        |   | $V_R=600V$ |      | 20   |      |

<sup>1)</sup>  $t_c$  is the time constant for the capacitive displacement current waveform (independent from  $T_j$ ,  $I_{LOAD}$  and  $di/dt$ ), different from  $t_{rr}$  which is dependent on  $T_j$ ,  $I_{LOAD}$  and  $di/dt$ . No reverse recovery time constant  $t_{rr}$  due to absence of minority carrier injection



# IDC04S60C

## CHIP DRAWING:



et4U.com

DataShee



# IDC04S60C

## FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

INFINEON TECHNOLOGIES

IDT04S60C

## Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

**Published by**  
**Infineon Technologies AG**  
**81726 Munich, Germany**

**© Infineon Technologies AG 2000**  
**All Rights Reserved**

DataSheet4U.com

## Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

## Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

## Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.